

Session Program

15-20 Jun 2014



2014 CAP Congress / Congrès de l'ACP 2014

***(R1-3) Ion Beam Analysis and Modification -
DCMMP / Analyse et modification de
faisceaux d'ions - DPMCM***

Laurentian University / Université Laurentienne
Sudbury, Ontario

Wednesday 18 June

08:45

(R1-3) Ion Beam Analysis and Modification - DCMMP / Analyse et modification de faisceaux d'ions - DPMCM

Session | **Location:** Laurentian University / Université Laurentienne, C-304, Sudbury, Ontario | **Convener:** François Schiettekatte

08:45–09:00 High Resolution Depth Profiling for Studying Titanium Oxidation

Speaker

Mr Mitchell Brocklebank

09:00–09:15

Characterization of PICASSO/PICO detectors using University of Montreal Tandem Van de Graaff accelerator

Speaker

Mathieu Laurin

09:15–09:30

Measurement of hyperuniformity in pure amorphous silicon

Speaker

Sjoerd Roorda

09:30–09:45

Defect complex evolution in semiconductors: long-range elastic interactions matter

Speaker

François Schiettekatte

09:45–10:00

Medium energy ions for thin films and monolayers

Speaker

Lyudmila Goncharova

10:00–10:30

Toward pump-probe experiments of defect dynamics with pulsed ion beams

Speaker

Peter Seidl

10:30